

ADVANCED FIB WORKSHOP 2025

09:30 – 09:40	Registration
09:40 – 09:50	Welcome & Introduction Dr. Chris BOOTHROYD (Senior Principle Scientist, FACTS, NTU)
09:50 – 10:20	Zeiss LaserFIB: A Versatile Workhorse for TEM Lamella Prep & Advanced Analytics Dr. Kasem BAU (Zeiss)
10:20 – 10:50	Keynote Talk: FIB Applications for Fabricating Atom Probe Tomography and Micromechanical Specimens Nanyang Asst. Prof. Yi-Sheng (Eason) CHEN (MSE, NTU)
10:50 – 11:05	Coffee/Tea Break
11:05 – 11:25	Keynote Talk: Making Nice Tips for Invizo 6000 Atom Probe Tomography Asst. Prof. Xipeng TAN (Department of Mechanical Engineering, NUS)
11:25 – 11:40	Engineering Interface in Bioinspired Ceramics for Damage-tolerant Applications Dr. Rohit Pratyush BEHERA (MAE, NTU)
11:40 – 11:55	From Low-dimensional Structure Analysis to In-situ Device Fabrication Dr. Yao WU (MSE, NUS)
11:55 – 12:10	The Extended Cut: FIB Lamella Preparation for In-situ TEM Patrick Wen Feng LI (MSE, NTU)
12:10 – 12:25	FIB Techniques for Fragile and Biased STEM Specimens Dr. Xin ZHOU (Institute for Functional Intelligent Materials, NUS)
12:25 – 13:30	Lunch Break
13:30 – 15:30	Hands-on Session I: Automated TEM lamella Preparation Andrew Han Keat TAN (Zeiss)
15:30 – 15:45	Coffee/Tea Break
15:45 – 17:45	Hands-on Session II: Specialized lamella Geometries (plan-view, inverted, top-down) Andrew Han Keat TAN (Zeiss)
17:45 – 17:50	Closing Remarks Dr. Lifei XI (FACTS, NTU)

Jointly organised by:

